Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	pplicant(s)/Patent under eexamination	
10/036,922	FECHER ET AL.		
Examiner	Art Unit		
Dmitry Levitan	2616		

SEARCHED					
Class	Subclass	Date	Examiner		
320	357 360 366				
379	32.01		DL		
	33	1/3/	04		
	39	74.1			
455	455-				
	457				
709	227				
	232				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
IEEE, EAST	2/13/06	DI		
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